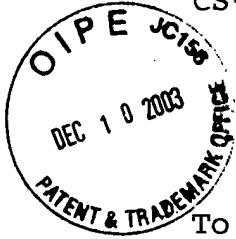


CS-02-023



December 1, 2003

To: Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572
28 Davis Avenue
Poughkeepsie, N.Y. 12603

Subject: | Serial No. 10/655,690 09/05/03 |
Nace Layadi et al.
IMPROVED IMP TiN BARRIER METAL
| PROCESS |
--- ---

INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation
In An Application.


The following Patents and/or Publications are submitted to
comply with the duty of disclosure under CFR 1.97-1.99 and
37 CFR 1.56. Copies of each document is included herewith.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being
deposited with the United States Postal Service as first class
mail in an envelope addressed to: Commissioner for Patents,
P.O. Box 1450, Alexandria, VA 22313-1450, on December 8, 2003.

Stephen B. Ackerman, Reg.# 37761

Signature/Date

 12/8/03

CS-02-023

U.S. Patent 6,326,690 to Wang et al., "Method of Titanium/Titanium Nitride Integration," discloses a Ti/TiN stack process.

U.S. Patent 6,297,555 to Zhao et al., "Method to Obtain a Low Resistivity and Conformity Chemical Vapor Deposition Titanium Film," discloses a two-step TiN barrier process.

U.S. Patent 6,043,148 to Peng et al., "Method of Fabricating Contact Plug," reveals a TiN process.

U.S. Patent 6,140,223 to Kim et al., "Methods of Forming Contacts for Integrated Circuits Using Chemical Vapor Deposition and Physical Vapor Deposition," discloses a multi-layer TiN barrier layer process.

Sincerely,

A handwritten signature in black ink, appearing to read 'SBA', with a long horizontal stroke extending to the right.

Stephen B. Ackerman,
Reg. No. 37761

Form PTO-1449 INFORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several sheets if necessary)	Docket Number (Optional) CS-02-023	Application Number 10/655,690
	Applicant Nace Layadi et al.	
	Filing Date 09/05/03	Group Art Unit

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILED DATE IF APPROPRIATE
	6326690	12/4/01	Wang et al.	257	751	12/14/00
	6297555	10/2/01	Zhao et al.	257	758	12/22/98
	6043148	3/28/00	Peng et al.	438	628	4/16/98
	6140223	10/31/00	Kim et al.	438	629	10/20/98

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
					YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.